

Shaping Organic Microcrystals Using Focused Ion Beam Milling

Supporting Information

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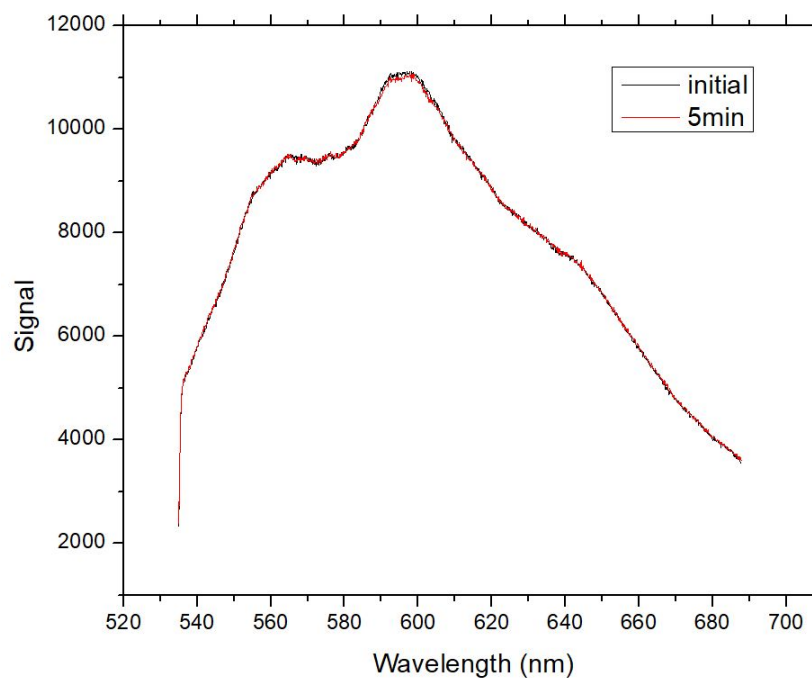


Figure S1. Photoluminescence intensity of the pure perylene crystal (without gold coating) before and after dipping into gold etchant.

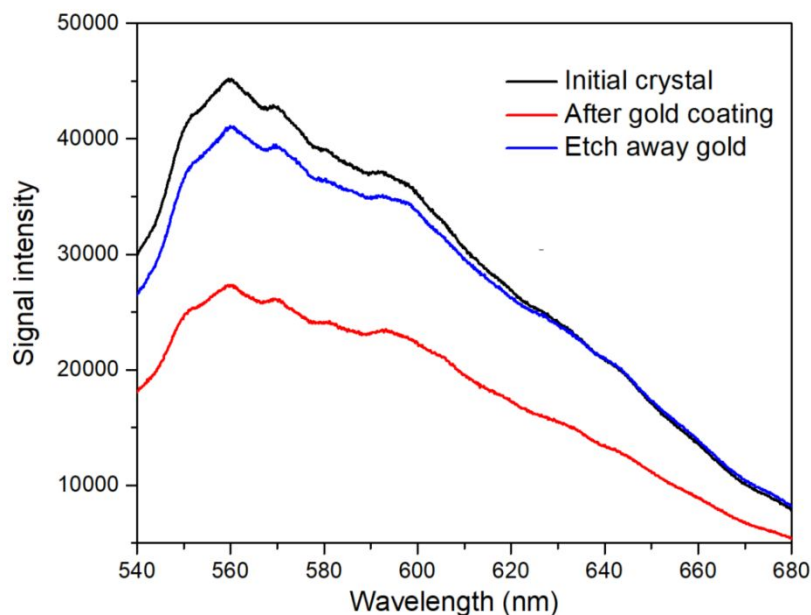


Figure S2. Photoluminescence intensity change of the Au-coated crystal without FIB exposure before and after the Au coating is etched away. This crystal was on the same substrate as a shaped crystal, but without direct exposure to ion beam.

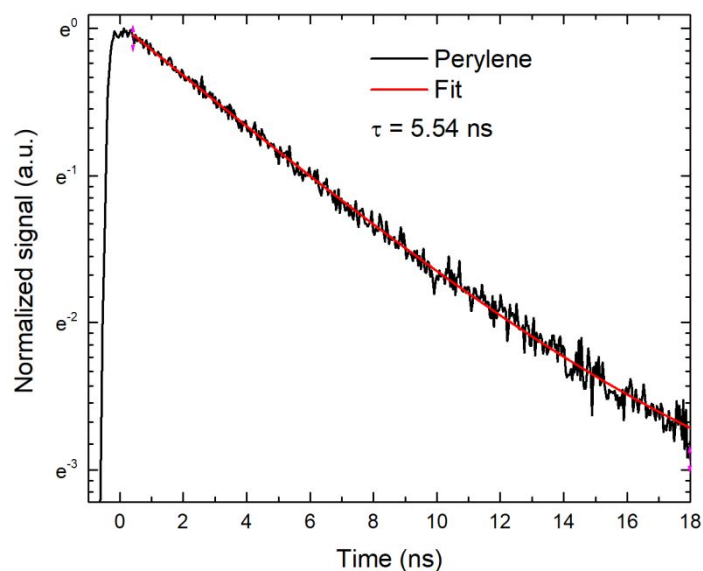


Figure S3. PL decays with biexponential fits of the original PER crystal excited by a 1 kHz laser. The signal is collected by a streak camera. The average lifetime here is 5.54 ns, which is longer than the result from single photon counting measurement using an 80 MHz laser.

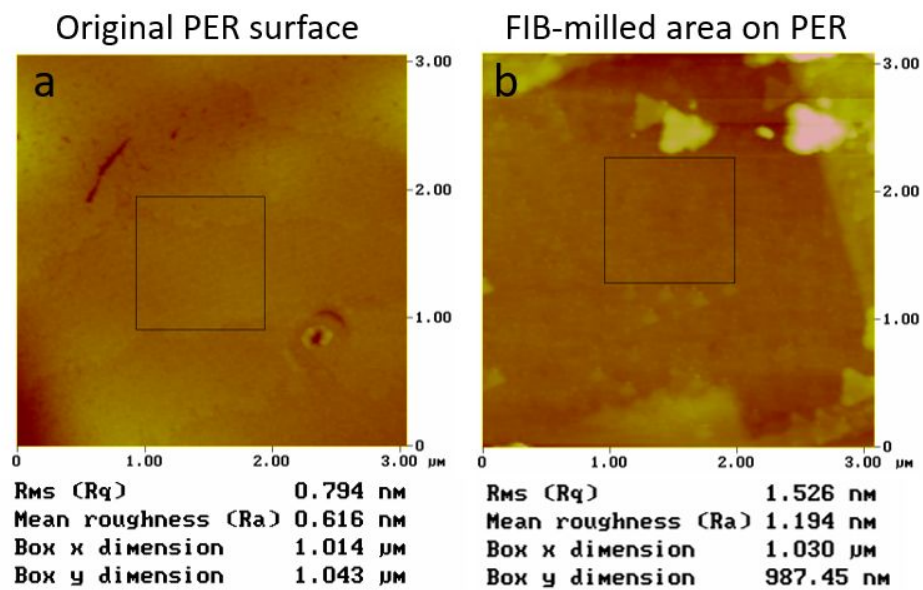


Figure S4. AFM roughness analysis of the Y-imprinted PER crystal (main text Figure 4) surface before (a) and after (b) FIB milling. The area in (b) is outside the Y shape, an area where the FIB beam removed material. The mean surface roughness increases from 0.6 nm to 1.2 nm after milling by the ion beam.